

Abstract

Electrical diagnostic circuit and method for the testing and/or the diagnostic analysis of an integrated circuit

The electrical diagnostic circuit for testing an integrated circuit comprises a number of external inputs (E), a plurality of essentially similar, series-connected switching units and a circuit output (116). The switching units are constructed to be controllable in such a manner that an input signal present at the internal input of the switching unit, in dependence on a control signal of the switching unit, can either be forwarded unchanged to the internal input of the switching unit in each case arranged downstream, or can be combined with the test signal in each case present at the external input (E).

(Figure 1)